



Product Change Notification / CENO-28OKTD637

Date:

09-Jul-2024

Product Category:

Clock and Timing - Clock and Data Distribution

PCN Type:

Manufacturing Change

Notification Subject:

CCB 6719 Final Notice: Qualification of MTAI as a new assembly site for selected SY100EP111, SY100EP195V, SY100EP196, SY89295U and SY89296 device families available in 32L TQFP (7x7x1.0mm) package.

Affected CPNs:

[CENO-28OKTD637_Affected_CPN_07092024.pdf](#)

[CENO-28OKTD637_Affected_CPN_07092024.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of MTAI as a new assembly site for selected SY100EP111, SY100EP195V, SY100EP196, SY89295U and SY89296 device families available in 32L TQFP (7x7x1.0mm) package.

Pre and Post Change Summary:

	Pre Change	Post Change
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Implementation Date																	
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Method to Identify Change:Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:February 2, 2024: Issued initial notification.
July 04, 2024: Issued final notification. Updated Notification subject and description of change to reflect the SY100EP195V device family from SY100EP15V. Attached the Qualification Report. Provided estimated first ship date to be on August 19, 2024.
July 09, 2024: Re-issued final notification to attach qualification report.

The change described in this PCN does not alter Microchip’s current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_CENO-280KTD637_Qual_Report.pdf](#)
[PCN_CENO-02VUYS211_Pre and Post Change_Summary.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

SY100EP195VTG
SY100EP196VTG
SY100EP195VTG-TR
SY100EP196VTG-TR
SY100EP111UTG-TR
SY100EP111UTG-TX
SY100EP111UTG
SY89296UTG
SY89296UTG-TR
SY89295UTG-TR
SY89295UTG

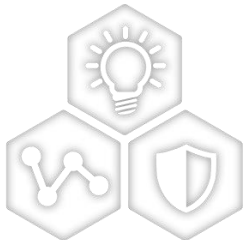
CCB 6719

Pre and Post Change Summary

PCN #: CENO-28OKTD637



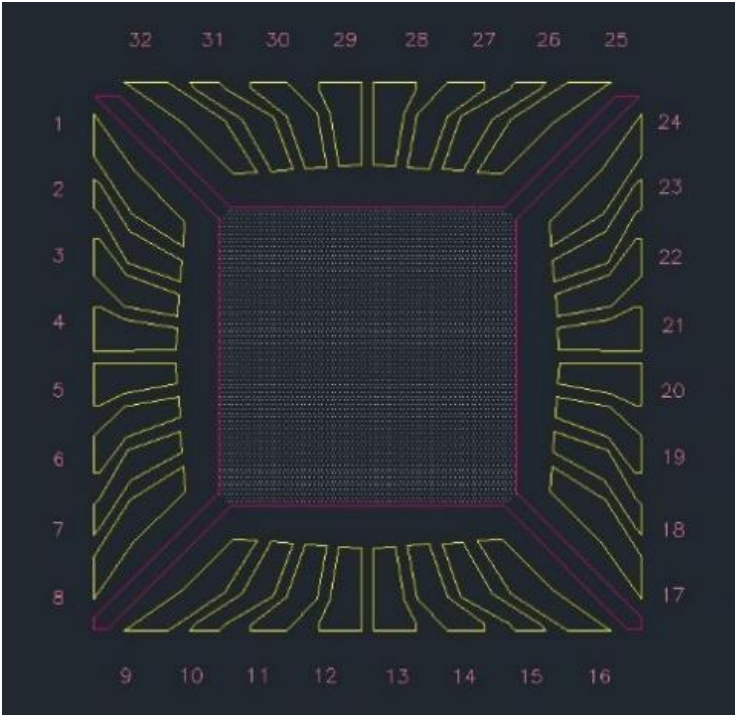
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



SMART | CONNECTED | SECURE

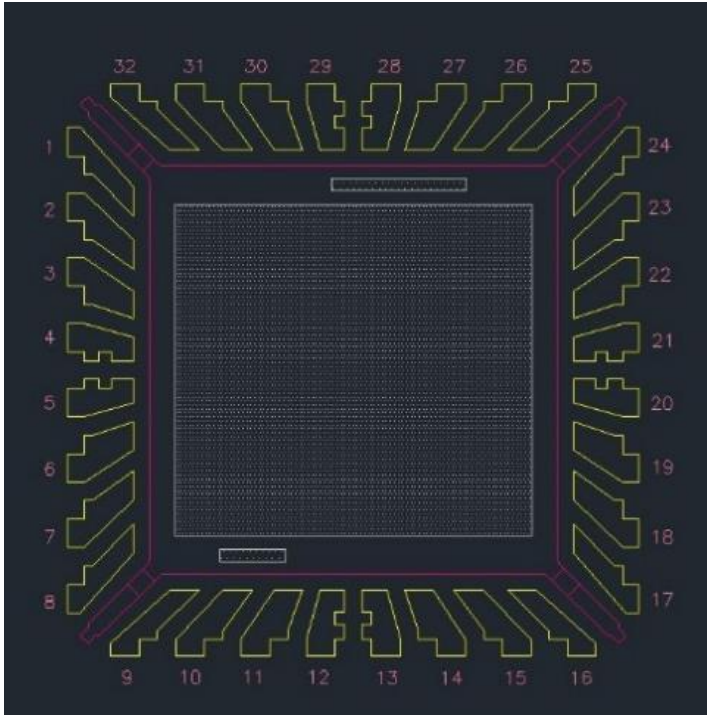
LEAD FRAME COMPARISON

ANAP



Lead Frame Material	C194
Paddle size	138 x 138 mils
DAP Surface Prep	NiPdAu

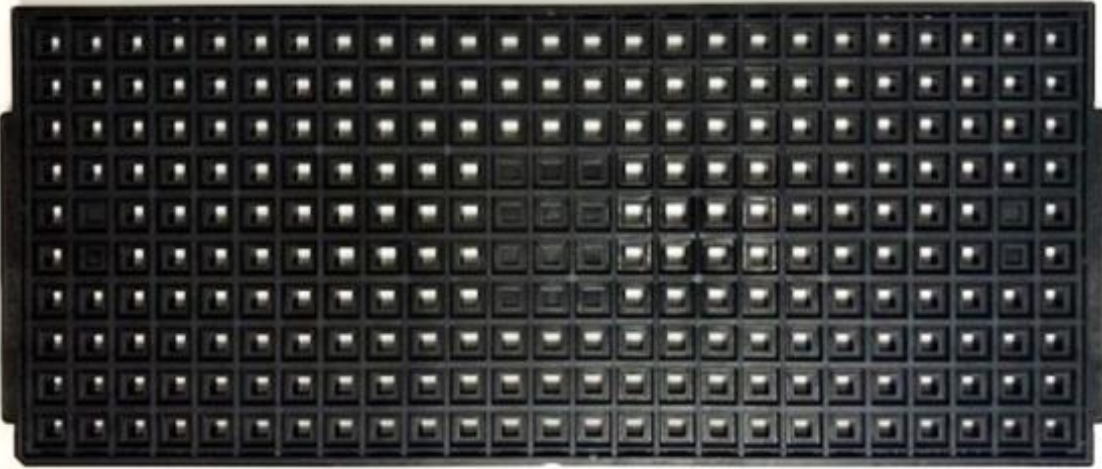
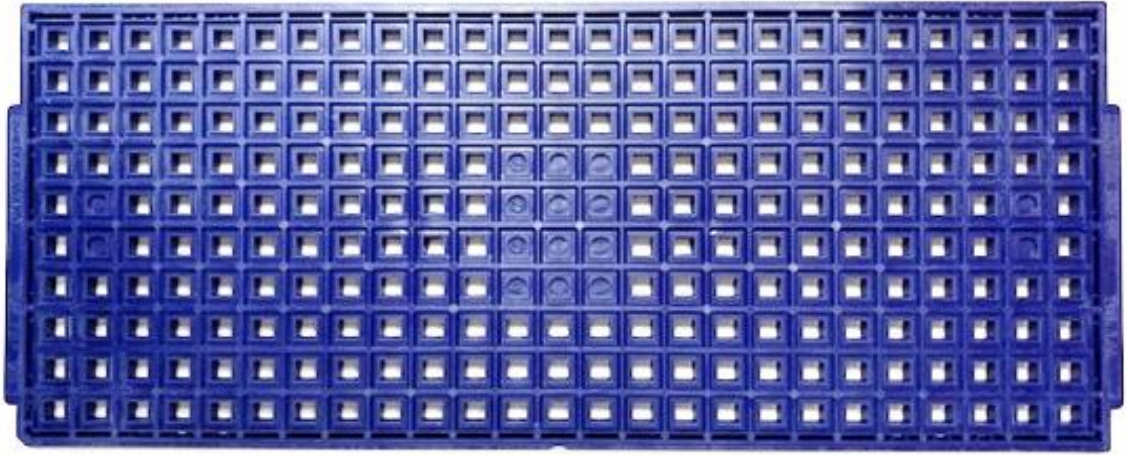
MTAI



Lead Frame Material	C7025
Paddle size	197 x 197 mils
DAP Surface Prep	Ag selective

Note: Not to scale

TRAY COMPARISON

ANAP	MTAI								
 <p>A black plastic tray with a grid of 100 square compartments, arranged in 10 rows and 10 columns. The tray has a slightly raised edge on the left side.</p>	 <p>A dark blue plastic tray with a grid of 100 square compartments, arranged in 10 rows and 10 columns. The tray has a slightly raised edge on the left side.</p>								
<table><tr><td>Color</td><td>Black</td></tr><tr><td>Baking</td><td>Bakeable</td></tr></table>	Color	Black	Baking	Bakeable	<table><tr><td>Color</td><td>Dark Blue</td></tr><tr><td>Baking</td><td>Non-bakeable</td></tr></table>	Color	Dark Blue	Baking	Non-bakeable
Color	Black								
Baking	Bakeable								
Color	Dark Blue								
Baking	Non-bakeable								



QUALIFICATION REPORT SUMMARY

RELIABILITY LABORATORY

PCN#: CENO-28OKTD637

Date:
June 25, 2024

Qualification of MTAI as a new assembly site for selected SY100EP111, SY100EP195V, SY100EP196, SY89295U and SY89296 device families available in 32L TQFP (7x7x1.0mm) package.



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PACKAGE QUALIFICATION REPORT

Purpose	Qualification of MTAI as a new assembly site for selected SY100EP111, SY100EP195V, SY100EP196, SY89295U and SY89296 device families available in 32L TQFP (7x7x1.0mm) package.
CN	E000209537
QUAL ID	R2400176 Rev. A.
MP CODE	2D8107T5XP12
Part No.	SY89295UTG
Bonding No.	BD-001944 Rev. 01
CCB No.:	6719
<u>Package</u>	
Type	32L TQFP
Package size	7 x 7 x 1.0 mm
<u>Lead Frame</u>	
Paddle size	197 x 197 mils
Material	C7025
Surface	Ag selective
Process	Stamped
Lead Lock	No
Part Number	10103206
Treatment	Roughening
<u>Material</u>	
Epoxy	QMI-519
Wire	Au wire
Mold Compound	G700HA
Plating Composition	Matte Sn



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PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MTAI243601887.000	TMPE219328826.130	2349B7U
MTAI243701126.000	TMPE219328826.130	2350DR6
MTAI243701127.000	TMPE219328826.130	2350DRA

Result

☒ Pass ☐ Fail ☐ _____

32L TQFP (7x7 mm) assembled by MTAI pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 1)	Electrical Test: +25°C and 85°C System: HP83K	JESD22-A113	693(0)	0/693		Good Devices
	Bake 150°C, 24 hrs.	JIP/ IPC/JEDEC J-STD-020E		693		
	85°C/85%RH Moisture Soak 168 hrs.			693		
	System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 265°C max					
	System: Vitronics Soltec MR1243					
	Electrical Test: +25°C and 85°C System: HP83K		693(0)	0/693	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: HP83K	JESD22- A104		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: + 85°C System: HP83K		231(0)	0/231	Pass	77 units / lot
	Bond Strength: Wire Pull (>4.00 grams)		15(0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: HP83K		231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: Vcc = 1.2 Volts System: HAST 6000X	JESD22- A110		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C and 85°C System: HP83K		231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs. System: TPS Bake Oven	JESD22- A103		0/45		45 units
	Electrical Test: +25°C and 85°C System: HP83K		45(0)	0/45	Pass	
Bond Strength Data Assembly	Wire Pull (>4.00 grams)	Mil. Std. 883-2011	30(0) Wires	0/30	Pass	
	Bond Shear (>18.00 grams)	CDF-AEC- Q100-001	30(0) bonds	0/30	Pass	